

A worldwide leader in precision measurement solutions



Cost-effective alternative to fully-automated wafer inspection systems

## Proforma<sup>™</sup> 300*i* - Manual Wafer Measurement Tool

Using MTI's proprietary non-contact capacitance probes, the Proforma 300*i* is fast, accurate and reliable. The Proforma 300*i* is capable of measuring wafer up to 300mm in diameter for thickness, total thickness variation (TTV) and bow.

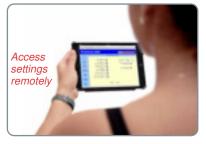


## Proforma<sup>™</sup> 300*i* - Specifications -

	Proforma 300i	Proforma 300Gi	Proforma 300 OEM i 1
Accuracy <sup>2</sup> :	±0.25 μm		
Repeatability <sup>3</sup> :	±0.25 μm		
Resolution:	0.05 μm		
Electrical Input (Voltage):	100 to 240VAC		
Electrical Input (Frequency):	50 to 60Hz		
Electrical Input (Power):	50 Watts		
Temperature (Operational):	15 to 40°C		
Response Time:	60ms		Custom
Dimensions (LxWxH):	482x330x279 mm		483x388x89 mm
Data Interfaces	RS232, Ethernet, USB, LCD		RS232, Ethernet
Known Supported Materials <sup>4</sup> :			
Si	•	•	•
Ge	•	•	•
InP GaAs	•	•	•
GaAs Weight:	12.3 kg	12.4 kg	5.9 kg

- 1 The OEM model consists of the acquisition system and probes only. As such, several parameters will be dependant on the custom installation parameters. Contact MTI Instruments to discuss custom applications and expected performance in these applications.
- 2 At constant 22°C.
- 3 Within limits of repositioning.
- 4 The ability to measure can vary dependant on several factors (such as bulk resistivity).





## Optional SEMI MF534-0707 Bow wafer ring.

Bow wafer ring not only allows for measurement of bow but also eliminates contact between the wafer and table, providing additional wafer protection.

P300i.09.04.2013.REV1.0

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